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(REV. 7-80) PATENT AND TRADEMARK OFFICE

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LIST OF MATERIALS CITED BY APPLICANT

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INVENTOR'S NAME:  
Jared ZERBE et al.

EXAMINER:  
Tung S. Lau

FILING DATE:  
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GROUP:  
2863

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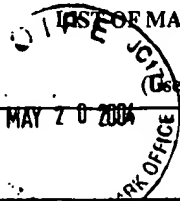
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EXAMINER

DATE CONSIDERED

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<b>FORM PTO-1449 U.S. DEPARTMENT OF COMMERCE</b> <b>(REV. 7-80) PATENT AND TRADEMARK OFFICE</b>				<b>ATTY. DOCKET NO.:</b> 57941.000037		<b>SERIAL NO.:</b> 09/776,550		
<div style="text-align: center;"> <b>LIST OF MATERIALS CITED BY APPLICANT</b>          (Use several sheets if necessary)       </div> <div style="text-align: center;">  </div>				<b>INVENTOR'S NAME:</b> Jared ZERBE et al.		<b>EXAMINER:</b> Tung S. Lau		
				<b>FILING DATE:</b> February 2, 2001		<b>GROUP:</b> 2863		
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EXAMINER <i>Tung Lau</i>					DATE CONSIDERED <i>10-1-04</i>			
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